

In the Specification:

Please amend paragraph [0021] on page 8 as follows:

Referring now to FIG. 2, there is illustrated a new method of setting up an OBIRCH circuit analysis that overcomes these problems. Those portions of the circuit arrangement that operate similar to the prior art arrangement carry the same reference numbers used in FIG. 1. Therefore, as shown, and according to the present invention, the separate power supply 30 has been eliminated with the constant voltage power supply 26 in addition to being used as the current source for providing current through the wires and conductors of the chip 10 being tested, is now connected to a diode circuit 34, comprised of a pair of common or bipolar diodes 36 and 38 connected to a series of Schottky diodes 40-52. In the embodiment shown, each of the Schottky diodes 40-52, connected cathode-to-anode, are selected to provide a precise voltage drop so that along with the two bipolar diodes 36 and 38, the constant voltage from power supply 26 results in a series of variable voltages [[56]] 54 at the anode of each of the Schottky diodes.